

Report No.: ZEWA2305000087RG01

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TEST REPORT

Application No.: ZEWA2305000087RG

Applicant: Quectel Wireless Solutions Co., Ltd.

Building 5, Shanghai Business Park Phase III (Area B), No.1016 Tianlin Road, **Address of Applicant:**

Minhang District, Shanghai, China 200233

Manufacturer: Quectel Wireless Solutions Co., Ltd.

Building 5, Shanghai Business Park Phase III (Area B), No.1016 Tianlin Road, Address of Manufacturer:

Minhang District, Shanghai, China 200233

EUT Description: LTE-A Cat 6 M.2 Module

Model No.: EM060K-NA

Trade Mark: Quectel

Standards:

FCC ID: XMR202307EM060KNA

47 CFR Part 2

47 CFR Part 96

Date of Receipt: 2023/05/12

Date of Test: 2023/05/25 to 2023/10/16

Date of Issue: 2023/10/16

PASS * Test Result:

In the configuration tested, the EUT detailed in this report complied with the standards specified above.

Authorized Signature:

Erom Li

Ervin Li Regulatory Manager



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Version

Revision Record						
Version Chapter Date Modifier Remark						
01		2023/10/16		Original		

Prepared By	Jack Huang) / Test Engineer
Checked By	Daniel Wang (Daniel Wang) / Reviewer



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2 **Test Summary**

2.1 LTE Band 42(3550-3600)/43(3600-3700)/48

Test Item	FCC Rule No.	Requirements	Test Result	Verdict	
Effective (Isotropic) Radiated Power Output Data	§2.1046, §96.41	EIRP ≤ 23dBm/10MHz	Section 1 of Appendix B.15&B.16&B.17	Pass	
Peak-Average Ratio	§96.41	FCC: Limit≤13 dB	Section 2 of Appendix B.15&B.16&B.17	Pass	
Bandwidth	§2.1049	OBW: No limit. EBW: No limit.	Section 3 of Appendix B.15&B.16&B.17	Pass	
Adjacent Channel Leakage Ratio	§96.41	the Adjacent Channel Leakage Ratio for End User Devices shall be at least 30 dB.	Section 4 of B.15&B.16&B.17	Pass	
Band Edges Compliance	§2.1051, §96.41	for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed -13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge.	Section 5 of Appendix B.15&B.16&B.17	Pass	
Spurious Emission at Antenna Terminals	§2.1051, §96.41	for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed -13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge. At all frequencies greater than B megahertz above the upper CBSD assigned channel edge and less than B megahertz below the lower CBSD-assigned channel edge, the conducted power of any	Section 6 of Appendix B.15&B.16&B.17	Pass	



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		End User Device emission shall not exceed -25 dBm/MHz. (2) Additional protection levels. Notwithstanding paragraph (e)(1) of this section, for CBSDs and End User Devices, the conducted power of emissions below 3540 MHz or above 3710 MHz shall not exceed -25 dBm/MHz, and the conducted power of emissions below 3530 MHz or above 3720 MHz shall not exceed -40dBm/MHz.		
Field Strength of Spurious Radiation	§2.1053, §96.41	for channel and frequency assignments made by a CBSD to End User Devices, the conducted power of any End User Device emission outside the fundamental emission (whether in or outside of the authorized band) shall not exceed –13 dBm/MHz within 0 to B megahertz (where B is the bandwidth in megahertz of the assigned channel or multiple contiguous channels of the End User Device) above the upper CBSD-assigned channel edge and within 0 to B megahertz below the lower CBSD-assigned channel edge. At all frequencies greater than B megahertz above the upper CBSD assigned channel edge and less than B megahertz below the lower CBSD-assigned channel edge, the conducted power of any End User Device emission shall not exceed –25 dBm/MHz. (2) Additional protection levels. Notwithstanding paragraph (e)(1) of this section, for CBSDs and End User Devices, the conducted power of emissions below 3540 MHz or above 3710 MHz shall not exceed –25 dBm/MHz, and the conducted power of emissions below 3530 MHz or above 3720 MHz shall not exceed –40dBm/MHz.	Section 7 of Appendix B.15&B.16&B.17	Pass
Frequency Stability	§2.1055, §96.41	Within authorized bands of operation/ frequency block.	Section 8 of Appendix B.15&B.16&B.17	Pass



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3 General Information

3.1 Details of Client

Applicant:	Quectel Wireless Solutions Co., Ltd.		
Address of Applicant:	Building 5, Shanghai Business Park Phase III (Area B), No.1016 Tianlin Road, Minhang District, Shanghai, China 200233		
Manufacturer:	Quectel Wireless Solutions Co., Ltd.		
Address of Manufacturer:	Building 5, Shanghai Business Park Phase III (Area B), No.1016 Tianlin Road, Minhang District, Shanghai, China 200233		

3.2 Test Location

Company:	SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch
Address: No. 1 Workshop, M-10, Middle section, Science & Technology Park District, Shenzhen, Guangdong, China	
Post code:	518057
Test engineer:	Jinhua Wei, Xing Guo

3.3 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

VCCI

The 3m Fully-anechoic chamber for above 1GHz, 10m Semi-anechoic chamber for below 1GHz, Shielded Room for Mains Port Conducted Interference Measurement and Telecommunication Port Conducted Interference Measurement of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-20026, R-14188, C-12383 and T-11153 respectively.

Innovation, Science and Economic Development Canada

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch has been recognized by ISED as an accredited testing laboratory.

CAB identifier: CN0006.

IC#: 4620C.

• FCC -Designation Number: CN1336

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch has been recognized as an accredited testing laboratory.

Designation Number: CN1336.

Test Firm Registration Number: 787754



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3.4 General Description of EUT

EUT Description:	LTE-A Cat 6 M.2 Module						
Model No.:	EM060K-NA						
Trade Mark:	Quectel	Quectel					
Hardware Version:	R1.0						
Software Version:	EM060KNAAAR01A	\02M2G					
Power Supply:	3.8V(DC Supply)						
Equipment class code:	CBE						
	RF Conducted	863550060	0001682				
IMEI:	RSE		550060001658 550060002060				
Antenna Type:	⊠ External, ☐ Inte	⊠ External, ☐ Integrated					
	LTE Band 42: -2.00dBi						
	LTE Band 43: -2.00dBi						
Antenna Gain:	LTE Band 48: -2.00dBi						
	Note: The antenna gain are derived from the gain information report provided by the manufacturer.						
	9kHz ~ 30MHz						
RF Cable:	2000MHz ~ 400 (1.1dB)	00MHz	4000MHz ~ 6000MHz (1.8dB)	6000MHz ~ 12750MHz (2.6dB)			
	Above 12750MHz (3.5dB)						
Remark:	-						

Remark:

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3.5 Test Mode

Test Mode	Test Modes Description
LTE/TM1	LTE system, QPSK modulation
LTE/TM2	LTE system, 16QAM modulation
Remark: The test mode(s) are selected according to relevant radio technology specifications.

3.6 Test Environment

Environment Parameter		101 kPa Selec	ed Values During Tests			
Relative Humidity		44-46	% RH Ambient			
Value		Temperature(°C)	Voltage(V)			
NTNV		22~23	3.7			
LTLV		-30	3.135			
LTHV	LTHV		4.4			
HTLV		50	3.135			
HTHV		50	4.4			
Remark:						
NV: Normal Voltage LV: Low		Extreme Test Voltage	HV: High Extreme Test Voltage			
NT: Normal Temperature LT: Low		Extreme Test Temperature	HT: High Extreme Test Temperature			

3.7 Description of Support Units

Description	Manufacturer	Model No.
Mother board	Quectel	N/A
Remark: all above the information of ta	able are provided by client.	



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3.8 Technical Specification

Characteristics	Description								
Radio System Type	□ LTE								
Supported Frequency Range	Band		TX				RX		
	LTE Band 42 (3550 to 3600 MHz)		3550 to 3600 MHz				3550 to 3600 MHz		
	LTE Band 43 (3600 to 3700 MHz)		3600 to 3700 MHz				3600 to 3700 MHz		
	LTE Band 48		3550 to	370	00 MHz		3550 to 3	3700 MHz	
	LTE Band42		⊠5 MHz	7	⊠10 MHz	\triangleright	15 MHz	⊠20 MHz	
Supported Channel Bandwidth	LTE Band43		⊠5 MHz	_	⊠10 MHz	\triangleright	15 MHz	⊠20 MHz	
	LTE Band48		⊠5 MHz ⊠10 MH		⊠10 MHz	\triangleright	☐15 MHz	⊠20 MHz	
Characteristics	Description								
	E-UTRA:	QP	SK	16	16QAM				
		4M4	49G7D	9G7D 4M49					
Designation of Emissions	LTE Band 42	9M0	9M00G7D 8M95W7D 13M5G7D 13M5W7D		//95W7D				
	(3550-3600)	131							
(Remark: the necessary		181	10G7D	18	8M0W7D				
bandwidth of which is the		4M4	49G7D	4M50W7D					
worst value from the	LTE Band 43	8M9	97G7D	91	И01W7D	QAM			
measured occupied	(3600-3700)	13N	3M5G7D 13M5W7D						
bandwidths for each type of		181	10G7D	18	BM0W7D				
channel bandwidth		4M	50G7D	41	M51W7D				
configuration.)	LTE Band 48	9M0	01G7D	81	//97W7D				
	LIL Dallu 40	13N	15G7D	13	BM5W7D				
		181	10G7D	18	BM0W7D			_	



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3.9 Test Frequencies

Test Mode	Bandwidth	TX / RX	RF Channel			
i est iviode	Dariuwiuiii	IA/KA	Low (L)	Middle (M)	High (H)	
			Channel 40115	Channel 43340	Channel 43565	
		TX	3552.5 MHz	3575 MHz	3597.5 MHz	
	5MHz	RX	Channel 40115	Channel 43340	Channel 43565	
		KA	3552.5 MHz	3575 MHz	3597.5 MHz	
			Channel 43140	Channel 43340	Channel 43540	
		TX	3555 MHz	3575 MHz	3595 MHz	
	10MHz	RX	Channel 43140	Channel 43340	Channel 43540	
LTE Band 42			3555 MHz	3575 MHz	3595 MHz	
(3550-3600)			Channel 43165	Channel 43340	Channel 43515	
,	451411-	TX	3557.5 MHz	3575 MHz	3592.5 MHz	
	TSMHZ	15MHz RX	Channel 43165	Channel 43340	Channel 43515	
			3557.5 MHz	3575 MHz	3592.5 MHz	
			Channel 43190	Channel 43340	Channel 43490	
		TX	3560 MHz	3575 MHz	3590 MHz	
	20MHz	DV	Channel 43190	Channel 43340	Channel 43490	
		RX	3560 MHz	3575 MHz	3590 MHz	

Test Mode	Bandwidth	TX / RX	RF Channel			
rest Mode			Low (L)	Middle (M)	High (H)	
	5MHz	TX/RX	Channel 43615	Channel44090	Channel 44565	
			3602.5 MHz	3650.0 MHz	3697.5 MHz	
	10MHz	TX/RX	Channel 43640	Channel44090	Channel 44540	
LTE Band 43			3605.0 MHz	3650.0 MHz	3695.0 MHz	
(3600-3700)	15MHz TX/RX	TV/DV	Channel 43665	Channel44090	Channel 44515	
		TX/RX	3607.5 MHz	3650.0 MHz	3692.5 MHz	
	20MHz TX/RX	TV/DV	Channel 43690	Channel44090	Channel 44490	
		3610 MHz	3650.0 MHz	3690.0 MHz		

Test Mode	Bandwidth	TX / RX	RF Channel			
rest Mode	Dariuwiuiii		Low (L)	Middle (M)	High (H)	
		TX/RX	Channel 55265	Channel55990	Channel 56715	
	5MHz		3552.5 MHz	3625.0 MHz	3697.5 MHz	
	10MHz TX/F	TX/RX	Channel 55290	Channel55990	Channel 56690	
LTE D 1 40			3555.0 MHz	3625.0 MHz	3695.0 MHz	
LTE Band 48		TV/DV	Channel 55315	Channel55990	Channel 56665	
		TX/RX	3557.5 MHz	3625.0 MHz	3692.5 MHz	
	20MHz TX/RX	TV/DV	Channel 55340	Channel55990	Channel 56640	
		3560.0 MHz	3625.0 MHz	3690.0 MHz		



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4 Description of Tests

4.1 Conducted Output Power

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.2.1

The transmitter output was connected to a calibrated coaxial cable, attenuator and power meter, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The power output at the transmitter antenna port was determined by adding the value of the cable insertion loss to the power reading. The tests were performed at three frequencies (low channel, middle channel and high channel) and on the highest power levels, which can be setup on the transmitters.

Remark: Reference test setup 1



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4.2 Effective (Isotropic) Radiated Power of Transmitter

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.8.4

Calculate power in dBm by the following formula:

ERP (dBm) = Conducted Power (dBm) + antenna gain (dBd)

EIRP(dBm) = Conducted Power (dBm) + antenna gain (dBi)

EIRP=ERP+2.15dB



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4.3 Occupied Bandwidth

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 4.2 & 4.3

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel, middle channel and high channel). The span of the analyzer shall be set to capture all products of the modulation process, including the emission skirts. The resolution bandwidth shall be set to as close to 1 percent of the selected span as is possible without being below 1 percent. The video bandwidth shall be set to 3 times the resolution bandwidth. Video averaging is not permitted. Where practical, a sampling detector shall be used since a peak or, peak hold, may produce a wider bandwidth than actual. The trace data points are recovered and are directly summed in linear terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5 percent of the total is reached and that frequency recorded. The process is repeated for the highest frequency data points. This frequency is recorded. The span between the two recorded frequencies is the occupied bandwidth.

Remark: Reference test setup 1

Test Settings

- The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
- RBW = 1 5% of the expected OBW
- VBW ≥ 3 x RBW
- Detector = Peak
- Trace mode = max hold
- Sweep = auto couple
- 7. The trace was allowed to stabilize
- 8. If necessary, steps 2 7 were repeated after changing the RBW such that it would be within
 - 1 5% of the 99% occupied bandwidth observed in Step 7



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4.4 Band Edge at Antenna Terminals

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 6.0

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyser, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at two frequencies (low channel and high channel).in the 1MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of 100kHz or 1% of the emission bandwidth of the fundamental emission of the transmitter may be employed. The EUT emission bandwidth is measured as the width of the signal between two points, outside of which all emission are attenuated at least 26dB below the transmitter power. The video bandwidth of the spectrum analyzer was set at thrice the resolution bandwidth. Detector Mode was set to rms.

Remark: Reference test setup 1

Test Settings

- 1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
- 2. Span was set large enough so as to capture all out of band emissions near the band edge
- 3. RBW > 1% of the emission bandwidth
- 4. VBW > 3 x RBW
- Detector = RMS
- Number of sweep points ≥ 2 x Span/RBW
- 7. Trace mode = trace average for continuous emissions, max hold for pulse emissions
- 8. Sweep time = auto couple
- 9. The trace was allowed to stabilize



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4.5 Spurious And Harmonic Emissions at Antenna Terminal

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 6.0

The transmitter output was connected to a calibrated coaxial cable, attenuator and Spectrum analyzer, the other end of which was connected to a Base Station Simulator. The Base Station Simulator was set to force the EUT to its maximum power setting. The tests were performed at three frequencies (low channel and high channel). The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. On any frequency outside a licensee's frequency block, the power of any emission shall be attenuated below the transmitter power (P) by at least 43 + 10 log(P) dB. Compliance with these provisions is based on the use of measurement instrumentation employing a resolution bandwidth of 1 MHz or greater. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

Remark: Reference test setup 1

Test Settings

- 1. Start frequency was set to 9kHz and stop frequency was set to at least 10* the fundamental frequency(Separated into at least two plots per channel)
- 2. Detector = RMS
- 3. Trace mode = trace average for continuous emissinos, max hold for pulse emissions
- 4. Sweep time = auto couple
- 5. The trace was allowed to stabilize
- 6. Please see test notes below for RBW and VBW settings



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4.6 Peak-Average Ratio

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.7.2

A peak to average ratio measurement is performed at the conducted port of the EUT. For WCDMA signals, the spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level. For GSM signals, an average and a peak trace are used on a spectrum analyzer to determine the largest deviation between the average and the peak power of the EUT in a bandwidth greater than the emission bandwidth. The traces are generated with the spectrum analyzer set to zero span mode.

Remark: Reference test setup 1

Test Settings

- The signal analyzer's CCDF measurement profile is enabled
- Frequency = carrier center frequency
- 3. Measurement BW > Emission bandwidth of signal
- 4. The signal analyzer was set to collect one million samples to generate the CCDF curve
- 5. The measurement interval was set depending on the type of signal analyzed. For continuous signals (>98% duty cycle), the measurement interval was set to 1ms. For burst transmissions, the spectrum analyzer is set to use an internal "RF Burst" trigger that is synced with an incoming pulse and the measurement interval is set to less than the duration of the "on time" of one burst to ensure that energy is only captured during a time in which the transmitter is operating at maximum power



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4.7 Field Strength of Spurious Radiation

Measurement Procedure: FCC KDB 971168 D01 V03r01 Section 5.8

Below 1GHz test procedure as below:

- 1). The EUT was powered ON and placed on a 80cm high table in the chamber. The antenna of the transmitter was extended to its maximum length.
- 2). The disturbance of the transmitter was maximized on the test receiver display by raising and lowering from 1m to 4m (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) the receive antenna and by rotating through 360° the turntable. After the fundamental emission was maximized, a field strength measurement was made.
- 3). Steps 1) and 2) were performed with the EUT and the receive antenna in both vertical and horizontal polarization.
- 4). Test the EUT in the lowest channel, the middle channel, the Highest channel.
- 5). The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 6). Repeat above procedures until all frequencies measured was complete.

E (dB μ V/m) = Measured amplitude level (dB μ V) + (Cable Loss (dB) + Antenna Factor (dB/m) – AMP(dB)) EIRP (dBm) = E (dB μ V/m) + 20 log D – 104.8; where D is the measurement distance in meters

Above 1GHz test procedure as below:

- 1) Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber
- 2) Calculate power in dBm by the following formula:

E (dB μ V/m) = Measured amplitude level (dB μ V) + (Cable Loss (dB) + Antenna Factor (dB/m) – AMP(dB)) EIRP (dBm) = E (dB μ V/m) + 20 log D – 104.8; where D is the measurement distance in meters

- 3). Test the EUT in the lowest channel, the middle channel the Highest channel
- 4). The radiation measurements are performed in X, Y, Z axis positioning. And found the X axis positioning which it is worse case, Only the test worst case mode is recorded in the report.
- 5). Repeat above procedures until all frequencies measured was complete

Remark1: Reference test setup 2

Remark2: The emission below 18G were measured at a 3m test distance, while emissions above 18GHz were measured at a 1m test distance. At a measurement distance of 1 meter the limit line was increased by 20*LOG(3/1) = 9.54 dB.

Remark: Reference test setup 2

Remark:

1) The field strength is calculated by adding the Antenna Factor, Cable Factor & Preamplifier gain. The basic equation with a sample calculation is as follows:

Level = Reading Level + AF(dB/m) + Factor(dB)

AF = Antenna Factor(dB/m)

Factor = Cable Factor(dB) - Preamplifier gain (dB)

Margin = Limit(dBm) - Level(dBm)

2) Scan from 9kHz to 40GHz, The disturbance between 9KHz to 30MHz and 18GHz to 40GHz was very low, and the harmonics were the highest point could be found when testing, so only the harmonics had been displayed. The amplitude of spurious emissions from the radiator which are attenuated more than 20dB below the limit need not be reported.

3) All modes have been tested, but only the worst case data displayed in this report.

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4.8 Frequency Stability / Temperature Variation

Measurement Procedure:

Frequency stability testing is performed in accordance with the guidelines of FCC KDB 971168 D01 V03r01; Section 9

- . The frequency stability of the transmitter is measured by:
- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Specification – The frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block. The frequency stability of the transmitter shall be maintained within ±0.00025% (±2.5 ppm) of the center frequency.

Time Period and Procedure:

- 1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Remark: Reference test setup 3



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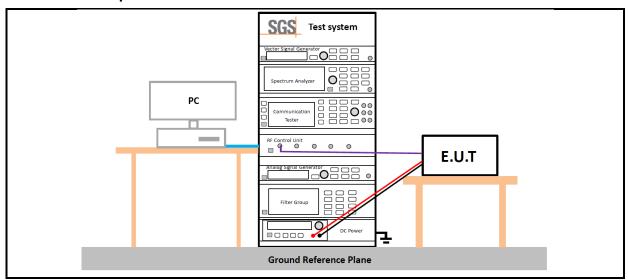
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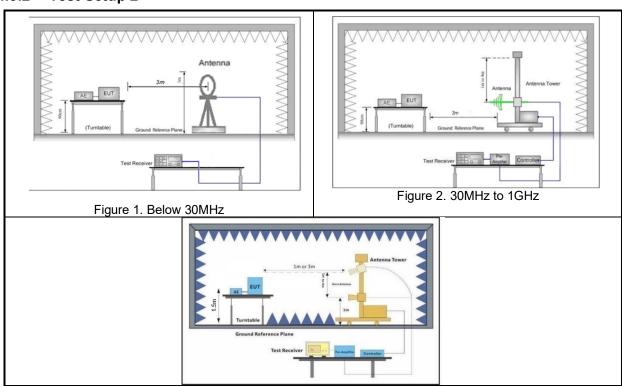
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4.9 Test Setups

4.9.1 **Test Setup 1**



4.9.2 **Test Setup 2**





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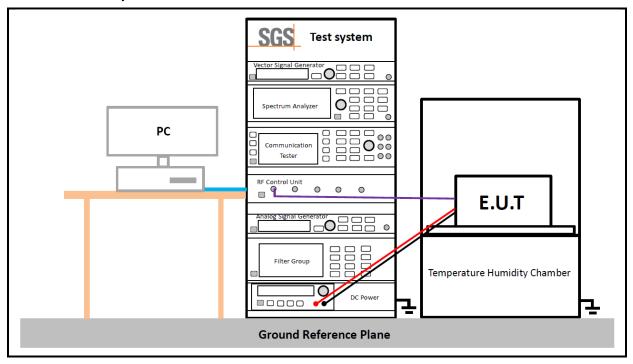


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Figure 3. above 1GHz

4.9.3 **Test Setup 3**





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4.10 Test Conditions

Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Mode LTE/TM1;LTE/TM2 Peak-to-Average Ratio Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Mode LTE/TM1;LTE/TM2 Bandwidth - Occupied Bandwidth Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Mode LTE/TM1;LTE/TM2 Bandwidth - Emission Bandwidth Test Case Test Conditions Test Conditions Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel) Test Mode LTE/TM1;LTE/TM2 Adjacent Channel Leakage Ratio Test Case Test Conditions	Transmit Output Power Data - Average Power, Total				
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Test Mode Adjacent Channel Leakage Ratio Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)	Test Setup	Test Setup 1			
Adjacent Channel Leakage Ratio Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)	RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)			
Test Case Test Conditions Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)	Test Mode	LTE/TM1;LTE/TM2			
Test Environment Ambient Climate & Rated Voltage Test Setup Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)		Adjacent Channel Leakage Ratio			
Test Setup 1 RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)	Test Case	Test Conditions			
RF Channels (TX) L, M, H (L= low channel, M= middle channel, H= high channel)	Test Environment	Ambient Climate & Rated Voltage			
	Test Setup	Test Setup 1			
Test Mode LTE/TM1	RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)			
f 1	Test Mode	LTE/TM1			



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Band Edges Compliance					
Test Case	Test Conditions				
Test Environment	Ambient Climate & Rated Voltage				
Test Setup	Test Setup 1				
RF Channels (TX)	L, H (L= low channel, H= high channel)				
Test Mode	LTE/TM1				
	Spurious Emission at Antenna Terminals				
Test Case	Test Conditions				
Test Environment	Ambient Climate & Rated Voltage				
Test Setup	Test Setup 1				
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
Test Mode	LTE/TM1				
	Field Strength of Spurious Radiation				
Test Case	Test Conditions				
Test Environment	Ambient Climate & Rated Voltage				
Test Setup	Test Setup 2				
RF Channels (TX)	L, M, H (L= low channel, M= middle channel, H= high channel)				
Test Mode	LTE/TM1 Remark: All bandwidth and modulation of LTE have been pre tested, and only the worst results are reflected in the report.				
	Frequency Stability				
Test Case	Test Conditions				
Test Environment	(1) -30 °C to +50 °C with step 10 °C at Rated Voltage				
Test Environment	(2) VL, VN and VH of Rated Voltage at Ambient Climate.				
Test Setup	Test Setup 3				
1 C3t Octup					
RF Channels (TX)	M (M= middle channel)				
·	M (M= middle channel) LTE/TM1				



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5 **Main Test Instruments**

RF conducted test						
Test Equipment	Manufacturer	Model No.	Inventory No.	Cal. date (yyyy/mm/dd)	Cal.Due date (yyyy/mm/dd)	
Humidity/ Temperature Indicator	Shanghai Meteorological Industry Factory	HTC-1	SZ-WRG-M-032	2023/02/17	2024/02/16	
Spectrum Analyzer	Rohde & Schwarz	FSV	SZ-WRG-M-012	2023/02/16	2024/02/15	
DC nower aunaly	HYELEC	HY3005B	SZ-WRG-M-044	2022/09/22	2023/09/21	
DC power supply	HTELEC	птоооо	3Z-WKG-W-044	2023/09/14	2024/09/13	
Digital Multimeter	VICTOR	VC890C	SZ-WRG-M-071	2022/12/22	2023/12/21	
Wideband Radio Communication Tester	Rohde & Schwarz	CMW500	SZ-WRG-M-033	2023/02/16	2024/02/15	
Wideband Radio Communication Tester	Anritsu	MT8821C	SZ-WRG-M-042	2023/05/25	2024/05/24	
Programmable Temperature & Humidity Chamber	Votsch Industrietechnik GmbH	VT 4002	SZ-WRG-M-075	2023/05/25	2024/05/24	
Signal Generator	KEYSIGHT	N5182A	SZ-WRG-M-041	2023/02/16	2024/02/15	



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Radiated spurious emissions						
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date	
EMI TEST RECEIVER	Rohde & Schwarz	ESR	SZ-WRG-M-047	2023/02/16	2024/02/15	
Signal &Spectrum Analyzer	Rohde & Schwarz	FSV	SZ-WRG-M-048	2023/02/16	2024/02/15	
Low Noise Amplifier 9K-3GHz	Tonscend	TAP9K3G32	SZ-WRG-M-049	2023/02/16	2024/02/15	
Low Noise Amplifier 30M- 8GHz	Tonscend	TAP30M8G30	SZ-WRG-M-050	2023/02/16	2024/02/15	
Low Noise Amplifier 1G- 18GHz	Tonscend	TAP01018050	SZ-WRG-M-051	2023/02/16	2024/02/15	
Low Noise Amplifier 18G- 40GHz	Tonscend	TAP18040048	SZ-WRG-M-052	2023/02/16	2024/02/15	
Active Loop Antenna 9kHz- 30MHz	SCHWARZBECK	FMZB 1519B	SZ-WRG-M-053	2022/01/16	2024/01/15	
TRILOG Breitband Antenne 30MHz- 1GHz	SCHWARZBECK	VULB 9168	SZ-WRG-M-054	2022/01/16	2024/01/15	
Double Ridge Horn Antenna 1GHz- 18GHz	SCHWARZBECK	BBHA 9120 D	SZ-WRG-M-055	2022/01/16	2024/01/15	
SHF-EHF Horn 15GHz-40GHz	SCHWARZBECK	BBHA 9170	SZ-WRG-M-056	2022/01/16	2024/01/15	
RSE Test Software	Tonscend	JS32-RSE V4.0.0	SZ-WRG-M-058	NCR	NCR	
RE Test Software	Tonscend	JS32-RE V4.0.0	SZ-WRG-M-059	NCR	NCR	
Radio Communication Tester	Anritsu	MT8821C	SZ-WRG-M-042	2023/05/25	2024/05/24	
Chamber	CRTSGSSAC966	N/A	SZ-WRG-C-063	2022/01/05	2025/01/04	
Humidity/ Temperature Indicator	Shanghai Meteorological Industry Factory	HTC-1	SZ-WRG-M-022	2023/02/17	2024/02/16	
Spectrum Analyzer	Keysight	N9020A	SZ-WRG-M-002	2022/11/18	2023/11/17	



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6 Measurement Uncertainty

For a 95% confidence level (k = 2), the measurement expanded uncertainties for defined systems, in

accordance with the recommendations of ISO 17025 as following:

No.	Item	Measurement Uncertainty
1	Radio Frequency	± 9.84Hz
2	Duty cycle	± 0.185%
3	Occupied Bandwidth	± 0.20%
4	RF conducted power	± 0.42dB
5	RF power density	± 1.97dB
6	Conducted Spurious emissions	± 0.42dB
		±4.8dB (30MHz-1GHz)
7	D 1 10 1 1 1 1 1 1 1	±4.68dB (1GHz-6GHz)
7	Radiated Spurious emission test(UE)	±4.52dB (6GHz-18GHz)
		±5.26dB (18GHz-40GHz)

Remark:

The U_{lab} (lab Uncertainty) is less than $U_{cispr/ETSI}$ (CISPR/ETSI Uncertainty), so the test results

- compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;

- non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.



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7 Appendixes

Appendix A.3	Appendix A.3 - WWAN Setup Photos-part96
Appendix B.15	LTE Band 42 (3550-3600)
Appendix B.16	LTE Band 43 (3600-3700)
Appendix B.17	LTE Band 48

---End of Report---



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